

Search Notes

Application/Control No.

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Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2821

SEARCHED

Class	Subclass	Date	Examiner
372	43.01- 46.016	3/14/2006	LA

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
372/43.01-46.016		3/14/2006	LA

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST prior art text search (see "Examiner Search Notes")	3/14/2006	LA
EAST interference text search (see "Examiner Search Notes")	3/14/2006	LA
IEEE Xplore text search	3/14/2006	LA
STIC search report performed on 20 September 2005	3/14/2006	LA
Consulted with Armando Rodriguez (primary in art unit 2828)	3/14/2006	LA